

<b>Notice of References Cited</b>	Application/Control No. 10/804,098	Applicant(s)/Patent Under Reexamination YAMAMOTO ET AL.	
	Examiner Anna L. Verderame	Art Unit 1756	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,470,628	11-1995	Tominaga et al.	428/64.4
*	B	US-2003/0039200	02-2003	Shintani et al.	369/275.1
*	C	US-2004/0085882	05-2004	Yamamoto et al.	369/094
*	D	US-7,041,430	05-2006	Miyamoto et al.	430/270.13
*	E	US-2002/0041564	04-2002	Yoshinari et al.	369/275.3
*	F	US-6,660,451	12-2003	Sakaue et al.	430/270.13
*	G	US-6,896,946	05-2005	Chen, Bing-Mau	428/64.1
*	H	US-7,063,876	06-2006	Nishihara et al.	428/64.1
*	I	US-2005/0207322	09-2005	Chen, Hon-Lun	369/275.2
*	J	US-2004/0219455	11-2004	Tseng et al.	430/270.11
*	K	US-4,905,215	02-1990	Hattori et al.	369/14
*	L	US-5,001,690	03-1991	Kamiya et al.	369/44.32
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 810 590	<del>05-1997</del>	<del>US</del> 12/1997	Rosen et al.	
	O	JP 03091128	04-1991	Japan	Hara et al.	
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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